


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585655	<b>Applicant(s)/Patent Under Reexamination</b>  TAKUMAI ET AL.
	<b>Examiner</b>  DEVONA E FAULK	<b>Art Unit</b>  2615

SEARCHED			
Class	Subclass	Date	Examiner
381	27,1,17,92,111,122,18,335	8/20/08	DEF
381	27,1,17,92,111,335,95-97,18	4/22,25/10	DEF
381	27,1,17,92,111,335,95-97,18,19,300,307,80	9/30/10,9/28/11	DEF
381	27,1,17,92,111,335,95-97,18,19,300,307,80	1/27/12	DEF

SEARCH NOTES		
Search Notes	Date	Examiner
assignee/inventor search	8/20/08	DEF
combined class/word search	8/20/08	DEF
additional search	4/22/10	DEF
additonal search	9/30/10,9,21,22,26,28/11	DEF
additional search	1/27/12	DEF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	combined class/word search	9/28/11	DEF
	combined class/word search	1/27/12	DEF

	/DEVONA E FAULK/ Primary Examiner.Art Unit 2614
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